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PATENT

Attorney Reference Number 3005-58065
Application Number 09/770,942

**Marked-up Version of Amended Claims
Pursuant to 37 C.F.R. §§ 1.121(c)**

1. (Amended) A method for analyzing a gas sample, comprising:
providing a gas sample or converting a sample to a gas sample;
increasing pressure applied to the gas sample to compress the sample to a smaller volume
and provide a pneumatically focused gas sample; and
analyzing the pneumatically focused gas sample by gas chromatography.
17. (Amended) The method according to claim 1 where analyzing the pneumatically
focused sample comprises reducing the pressure of the carrier-pneumatic focusing gas
simultaneously with or subsequent to a pneumatically focused sample being injected onto a
separatory column [or a spectrometric cell].
31. (Amended) The method according to claim 1 where analytes from the
pneumatically focused sample are determined by a detector selected from the group consisting of
FID, IR, FTIR, NDIR, ECD, TCD, [NPO] NPD, [FPO] FPD, UV/Visible detectors, and
combinations thereof.
37. (Amended) A method for analyzing an air sample, comprising:
collecting an air sample;
increasing the pressure of the sample to a pressure of from about 100 psi to about 15,000
psi to pneumatically focus the air sample; and
analyzing the pneumatically focused sample in real time using a gas chromatograph [or a
spectrometer].
73. (Amended) The method according to claim [73] 72 and providing the sample to a
column within a period of less than about 1 second.
74. (Amended) The method according to claim [55] 73 and providing the sample to a
column within a period of less than about 1 millisecond.